

September 2009

# 4N29M, 4N30M, 4N32M, 4N33M, H11B1M, TIL113M General Purpose 6-Pin Photodarlington Optocoupler

#### **Features**

- High sensitivity to low input drive current
- Meets or exceeds all JEDEC Registered Specifications
- UL, C-UL approved, File #E90700, Volume 2
- IEC 60747-5-2 approved (ordering option V)

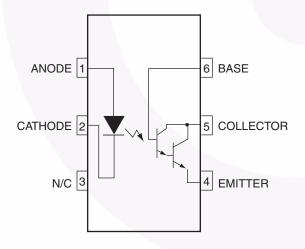
## **Applications**

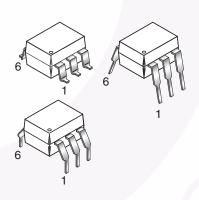
- Low power logic circuits
- Telecommunications equipment
- Portable electronics
- Solid state relays
- Interfacing coupling systems of different potentials and impedances

### **Description**

The 4N29M, 4N30M, 4N32M, 4N33M, H11B1M and TIL113M have a gallium arsenide infrared emitter optically coupled to a silicon planar photodarlington.

#### **Schematic**





**Absolute Maximum Ratings** (T<sub>A</sub> = 25°C unless otherwise specified.)
Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Value	Units
TOTAL DEVICE			1
T <sub>STG</sub>	Storage Temperature	-50 to +150	°C
T <sub>OPR</sub>	Operating Temperature	-40 to +100	°C
T <sub>SOL</sub>	Lead Solder Temperature (Wave)	260 for 10 sec	°C
P <sub>D</sub>	Total Device Power Dissipation @ T <sub>A</sub> = 25°C	250	mW
	Derate above 25°C	3.3	mW/°C
EMITTER			•
I <sub>F</sub>	Continuous Forward Current	80	mA
V <sub>R</sub>	Reverse Voltage	3	V
I <sub>F</sub> (pk)	Forward Current – Peak (300µs, 2% Duty Cycle)	3.0	А
P <sub>D</sub>	LED Power Dissipation @ T <sub>A</sub> = 25°C	150	mW
	Derate above 25°C	2.0	mW/°C
DETECTOR			
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	30	V
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	30	V
BV <sub>ECO</sub>	Emitter-Collector Breakdown Voltage	5	V
P <sub>D</sub>	Detector Power Dissipation @ T <sub>A</sub> = 25°C	150	mW
	Derate above 25°C	2.0	mW/°C
I <sub>C</sub>	Continuous Collector Current	150	mA

# 查询"4N29M"供应商 Electrical Characteristics (T<sub>A</sub> = 25°C Unless otherwise specified.)

## **Individual Component Characteristics**

Symbol	Parameter	Test Conditions	Device	Min.	Тур.	Max.	Unit
EMITTER			1				
V <sub>F</sub>	Input Forward Voltage*	I <sub>F</sub> = 10mA	4NXXM		1.2	1.5	V
			H11B1M, TIL113M	0.8	1.2	1.5	
I <sub>R</sub>	Reverse Leakage Current*	$V_{R} = 3.0V$	4NXXM		0.001	100	μΑ
		V <sub>R</sub> = 6.0V	H11B1M, TIL113M		0.001	10	
С	Capacitance*	$V_F = 0V$ , $f = 1.0MHz$	All		150		pF
DETECTO	PR		•				
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage*	$I_C = 1.0 \text{mA}, I_B = 0$	4NXXM,	30	60		V
			TIL113M				
			H11B1M	25	60		
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage*	$I_C = 100 \mu A, I_E = 0$	All	30	100		V
BV <sub>ECO</sub>	Emitter-Collector Breakdown Voltage*	$I_E = 100 \mu A, I_B = 0$	4NXXM	5.0	10		V
			H11B1M, TIL113M	7	10		
I <sub>CEO</sub>	Collector-Emitter Dark Current*	V <sub>CE</sub> = 10V, Base Open	All		1	100	nA

#### **Transfer Characteristics**

Symbol	Parameter	<b>Test Conditions</b>	Device	Min.	Тур.	Max.	Unit
DC CHARA	CTERISTICS			-			1
I <sub>C(CTR)</sub>	Collector Output Current*(1, 2)	I <sub>F</sub> = 10mA, V <sub>CE</sub> = 10V, I <sub>B</sub> = 0	4N32M, 4N33M	50 (500)			mA (%)
			4N29M, 4N30M	10 (100)			
		$I_F = 1 \text{mA}, V_{CE} = 5 \text{V}$	H11B1M	5 (500)			
		$I_F = 10$ mA, $V_{CE} = 1$ V	TIL113M	30 (300)			
V <sub>CE(SAT)</sub>	Saturation Voltage*(2)	$I_F = 8mA, I_C = 2.0mA$	4NXXM			1.0	V
			TIL113M	1		1.25	1
		$I_F = 1mA$ , $I_C = 1mA$	H11B1M			1.0	
AC CHARAC	CTERISTICS						
t <sub>on</sub>	Turn-on Time	$I_F = 200 \text{mA}, I_C = 50 \text{mA}, V_{CC} = 10 \text{V}, R_L = 100 \Omega$	4NXXM, TIL113M			5.0	μs
		$I_F = 10 \text{mA}, V_{CE} = 10 \text{V},$ $R_L = 100 \Omega$	H11B1M		25		
<sup>t</sup> off	Turn-off Time	$I_F = 200 \text{mA}, I_C = 50 \text{mA},$ $V_{CC} = 10 \text{V}, R_L = 100 \Omega$	4N32M, 4N33M, TIL113M			100	μs
			4N29M, 4N30M			40	
		$I_F = 10 \text{mA}, V_{CE} = 10 \text{V},$ $R_L = 100 \Omega$	H11B1M		18		
BW	Bandwidth <sup>(3, 4)</sup>				30		kHz

# **Electrical Characteristics** (T<sub>A</sub> = 25°C Unless otherwise specified.) (Continued)

#### **Isolation Characteristics**

Symbol	Characteristic	Test Conditions	Device	Min.	Тур.	Max.	Units
V <sub>ISO</sub>	Input-Output Isolation Voltage <sup>(5)</sup>	f = 60Hz, t = 1 sec.	All	7500			V <sub>AC</sub> PEAK
		VDC	4N32M*	2500			V
		VDC	4N33M*	1500			
R <sub>ISO</sub>	Isolation Resistance <sup>(5)</sup>	V <sub>I-O</sub> = 500VDC	All	10 <sup>11</sup>			Ω
C <sub>ISO</sub>	Isolation Capacitance <sup>(5)</sup>	$V_{I-O} = \emptyset$ , $f = 1MHz$	All		0.8		pF

<sup>\*</sup> Indicates JEDEC registered data.

#### Notes:

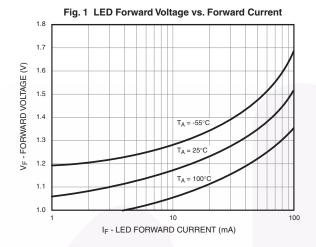
- 1. The current transfer  $\text{ratio}(I_{\text{C}}/I_{\text{F}})$  is the ratio of the detector collector current to the LED input current.
- 2. Pulse test: pulse width =  $300\mu s$ , duty cycle  $\leq 2.0\%$ .
- 3.  $I_F$  adjusted to  $I_C$  = 2.0mA and  $I_C$  = 0.7mA rms.
- 4. The frequency at which  $I_C$  is 3dB down from the 1kHz value.
- 5. For this test, LED pins 1 and 2 are common, and phototransistor pins 4, 5 and 6 are common.

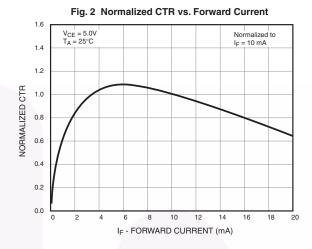
## Safety and Insulation Ratings

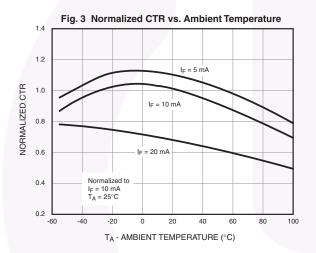
As per IEC 60747-5-2, this optocoupler is suitable for "safe electrical insulation" only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

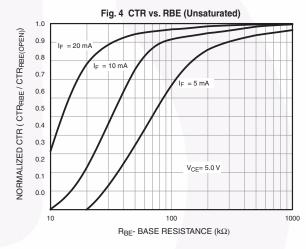
Symbol	Parameter	Min.	Тур.	Max.	Unit
	Installation Classifications per DIN VDE 0110/1.89 Table 1				
	For Rated Main Voltage < 150Vrms		I-IV		
	For Rated Main voltage < 300Vrms		I-IV		
	Climatic Classification		55/100/21		
	Pollution Degree (DIN VDE 0110/1.89)		2		
CTI	Comparative Tracking Index	175			
V <sub>PR</sub>	Input to Output Test Voltage, Method b, V <sub>IORM</sub> x 1.875 = V <sub>PR</sub> , 100% Production Test with tm = 1 sec, Partial Discharge < 5pC	1594			V <sub>peak</sub>
	Input to Output Test Voltage, Method a, V <sub>IORM</sub> x 1.5 = V <sub>PR</sub> , Type and Sample Test with tm = 60 sec, Partial Discharge < 5pC	1275		<u> </u>	V <sub>peak</sub>
V <sub>IORM</sub>	Max. Working Insulation Voltage	850			V <sub>peak</sub>
V <sub>IOTM</sub>	Highest Allowable Over Voltage	6000			V <sub>peak</sub>
	External Creepage	7			mm
	External Clearance	7			mm
	Insulation Thickness	0.5			mm
RIO	Insulation Resistance at Ts, V <sub>IO</sub> = 500V	10 <sup>9</sup>			Ω

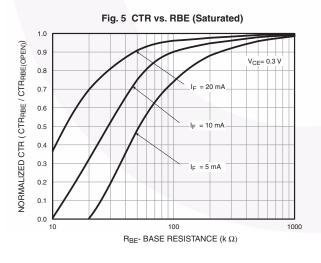
### Typical Performance Curves

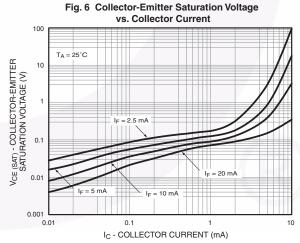






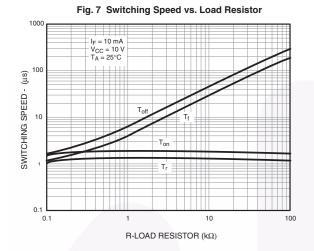


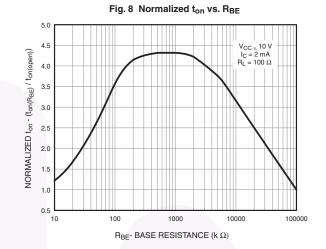


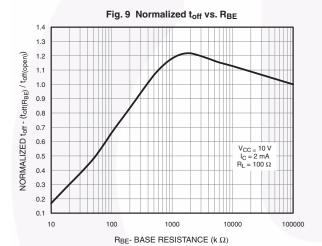


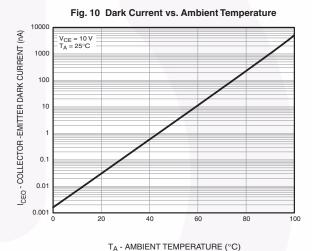
# 查询"4N29M"供应商 Typical Performa

### Typical Performance Curves (Continued)









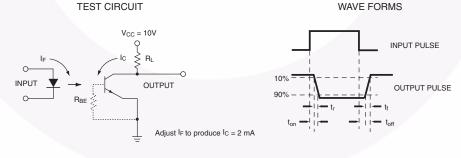
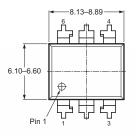
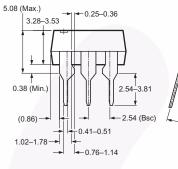


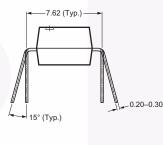
Figure 11. Switching Time Test Circuit and Waveforms

# **Package Dimensions**

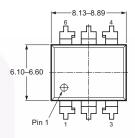
#### **Through Hole**

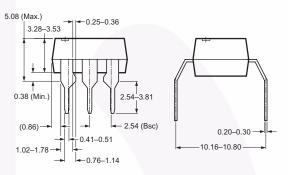




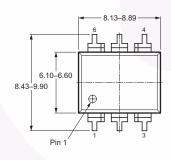


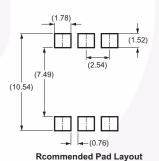
### 0.4" Lead Spacing

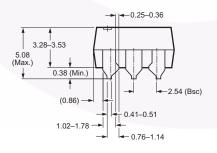


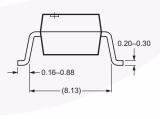


#### **Surface Mount**







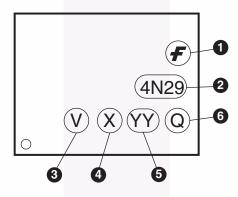


**Note:** All dimensions in mm.

# 查询"4N29M"供应商 Ordering Information

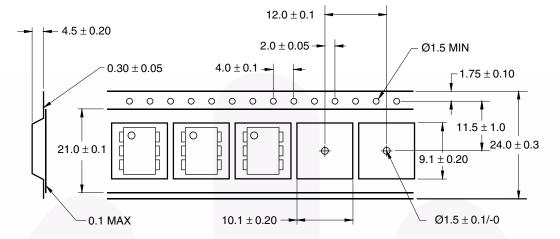
Suffix	Example	Option
No Suffix	4N32M	Standard Through Hole Device (50 units per tube)
S	4N32SM	Surface Mount Lead Bend
SR2	4N32SR2M	Surface Mount; Tape and Reel (1,000 units per reel)
Т	4N32TM	0.4" Lead Spacing
V	4N32VM	VDE 0884
TV	4N32TVM	VDE 0884, 0.4" Lead Spacing
SV	4N32SVM	VDE 0884, Surface Mount
SR2V	4N32SR2VM	VDE 0884, Surface Mount, Tape & Reel (1,000 units per reel)

# **Marking Information**



Definitions					
1	Fairchild logo				
2	Device number				
3	VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table)				
4	One digit year code, e.g., '7'				
5	Two digit work week ranging from '01' to '53'				
6	Assembly package code				

# Tape Dimensions

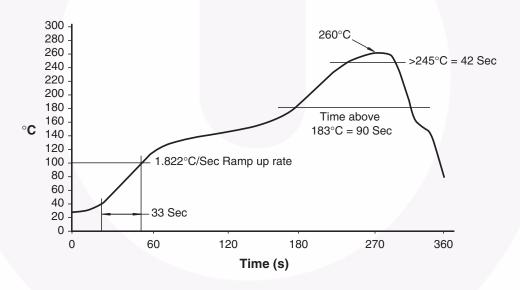


User Direction of Feed -----

#### Note:

All dimensions are in millimeters.

# **Reflow Soldering Profile**









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